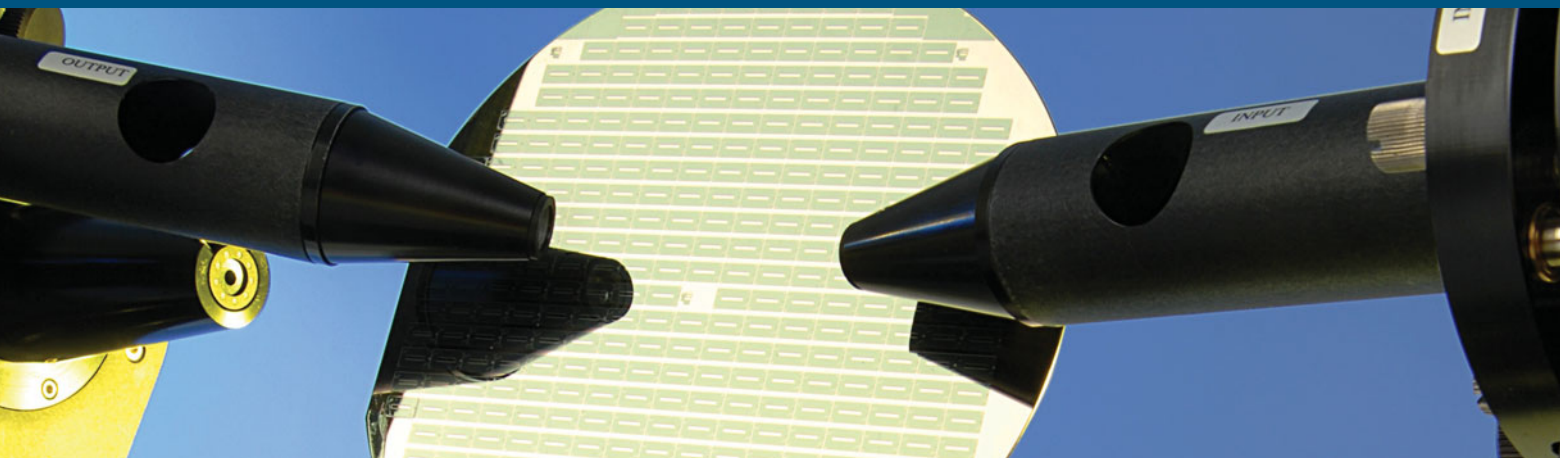




J.A. Woollam Co., Inc.

Ellipsometry Solutionssm for your Thin Film Characterization.



J.A. Woollam Co. has the world's widest variety of **Spectroscopic Ellipsometers** with **8** different models to non-destructively characterize thin film thickness and optical constants. After twenty-four years, over **15,000** samples characterized in our lab, and over **140** patents – we are the Ellipsometry Experts.

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H	Li	Na	K	Rb	Cs	Fr	B	C	N	O	F	Ne	He
Be	Mg		Ca	Sr	Ba	Ra	Al	Si	P	S	Cl	Ar	
			Sc	Y	La	Ac							
			Ti	Zr	Hf	Rf							
			V	Nb	Ta	Db							
			Cr	Mo	W	Sg							
			Mn	Tc	Re	Bh							
			Fe	Ru	Os	Hs							
			Co	Rh	Ir	Mt							
			Ni	Pd	Pt	Ds							
			Cu	Ag	Au	Rg							
			Zn	Cd	Hg	Cn							
			Ga	In	Tl	Utl							
			Ge	Sn	Pb	Uuq							
			As	Sb	Bi	Uup							
			Se	Te	Po	Uuh							
			Br	I	At	Uus							
			Kr	Xe	Rn	Uuo							

Ce	Pr	Nd	Pm	Sm	Eu	Gd	Tb	Dy	Ho	Er	Tm	Yb	Lu
Th	Pa	U	Np	Pu	Am	Cm	Bk	Cf	Es	Fm	Md	No	Lr

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 mischmet cathode solar ener superconduct
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